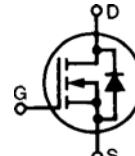


HiPerFET™ Power MOSFETs Q Class

IXFH/IXFT12N100Q
IXFH/IXFT10N100Q

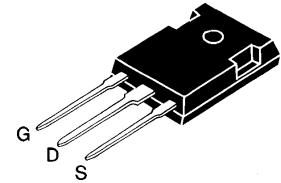
N-Channel Enhancement Mode
Avalanche Rated
Low Q_g, High dv/dt

V _{DSS}	I _{D25}	R _{DS(on)}
1000 V	12 A	1.05 Ω
1000 V	10 A	1.20 Ω
t_{rr} ≤ 250 ns		

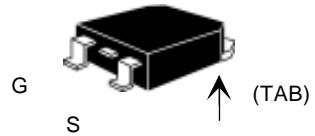


Symbol	Test Conditions	Maximum Ratings		
V _{DSS}	T _J = 25°C to 150°C	1000		V
V _{DGR}	T _J = 25°C to 150°C; R _{GS} = 1 MΩ	1000		V
V _{GS}	Continuous	±20		V
V _{GSM}	Transient	±30		V
I _{D25}	T _C = 25°C	12N100Q	12	A
		10N100Q	10	A
I _{DM}	T _C = 25°C, pulse width limited by T _{JM}	12N100Q	48	A
		10N100Q	40	A
I _{AR}	T _C = 25°C	12N100Q	12	A
		10N100Q	10	A
E _{AR}	T _C = 25°C		30	mJ
dv/dt	I _S ≤ I _{DM} , di/dt ≤ 100 A/μs, V _{DD} ≤ V _{DSS} , T _J ≤ 150°C, R _G = 2 Ω		5	V/ns
P _D	T _C = 25°C	300		W
T _J		-55 ... +150		°C
T _{JM}		150		°C
T _{stg}		-55 ... +150		°C
T _L	1.6 mm (0.063 in) from case for 10 s	300		°C
M _d	Mounting torque	1.13/10	Nm/lb.in.	
Weight		TO-247 AD	6	g
		TO-268	4	g
Symbol	Test Conditions	Characteristic Values (T _J = 25°C, unless otherwise specified)		
		min.	typ.	max.
V _{DSS}	V _{GS} = 0 V, I _D = 3 mA	1000		V
V _{GS(th)}	V _{DS} = V _{GS} , I _D = 4 mA	2.5		V
I _{GSS}	V _{GS} = ±20 V _{DC} , V _{DS} = 0		±100	nA
I _{DSS}	V _{DS} = 0.8 • V _{DSS} V _{GS} = 0 V	T _J = 25°C T _J = 125°C	50 1	μA mA
R _{DS(on)}	V _{GS} = 10 V, I _D = 0.5 I _{D25}	12N100Q 10N100Q	1.05 1.20	Ω
	Pulse test, t ≤ 300 μs, duty cycle d ≤ 2 %			

TO-247 AD (IXFH)



TO-268 (D3) (IXFT)



G = Gate D = Drain
S = Source TAB = Drain

Features

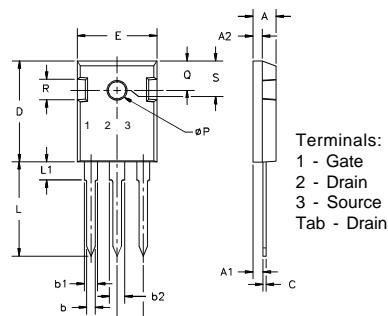
- IXYS advanced low Q_g process
- Low gate charge and capacitances
 - easier to drive
 - faster switching
- International standard packages
- Low R_{DS(on)}
- Unclamped Inductive Switching (UIS) rated
- Molding epoxies meet UL 94 V-0 flammability classification

Advantages

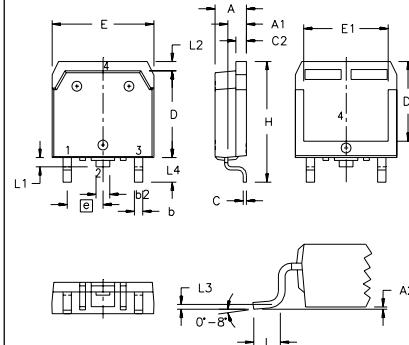
- Easy to mount
- Space savings
- High power density

Symbol	Test Conditions	Characteristic Values		
		min.	typ.	max.
g_{fs}	$V_{DS} = 15 \text{ V}; I_D = 0.5 \cdot I_{D25}$, pulse test	4	10	S
C_{iss} C_{oss} C_{rss}	$V_{GS} = 0 \text{ V}, V_{DS} = 25 \text{ V}, f = 1 \text{ MHz}$	2900		pF
		315		pF
		50		pF
$t_{d(on)}$ t_r $t_{d(off)}$ t_f	$V_{GS} = 10 \text{ V}, V_{DS} = 0.5 \cdot V_{DSS}, I_D = 0.5 \cdot I_{D25}$ $R_G = 2 \Omega$ (External),	20		ns
		23		ns
		40		ns
		15		ns
$Q_{g(on)}$ Q_{gs} Q_{gd}	$V_{GS} = 10 \text{ V}, V_{DS} = 0.5 \cdot V_{DSS}, I_D = 0.5 \cdot I_{D25}$	90		nC
		30		nC
		40		nC
R_{thJC}			0.42	K/W
R_{thCK}	(TO-247)		0.25	K/W

Symbol	Test Conditions	Characteristic Values		
		min.	typ.	max.
I_s	$V_{GS} = 0 \text{ V}$		12	A
I_{SM}	Repetitive; pulse width limited by T_{JM}		48	A
V_{SD}	$I_F = I_s, V_{GS} = 0 \text{ V}$, Pulse test, $t \leq 300 \mu\text{s}$, duty cycle $d \leq 2 \%$		1.5	V
t_{rr} Q_{RM} I_{RM}	$I_F = I_s, -di/dt = 100 \text{ A}/\mu\text{s}, V_R = 100 \text{ V}$	200		ns
		0.6		μC
		7		A

TO-247 AD (IXFH) Outline


Dim.	Millimeter Min.	Millimeter Max.	Inches Min.	Inches Max.
A	4.7	5.3	.185	.209
A ₁	2.2	2.54	.087	.102
A ₂	2.2	2.6	.059	.098
b	1.0	1.4	.040	.055
b ₁	1.65	2.13	.065	.084
b ₂	2.87	3.12	.113	.123
C	4	8	.016	.031
D	20.80	21.46	.819	.845
E	15.75	16.26	.610	.640
e	5.20	5.72	.205	.225
L	19.81	20.32	.780	.800
L1		4.50		.177
ØP	3.55	3.65	.140	.144
Q	5.89	6.40	0.232	0.252
R	4.32	5.49	.170	.216
S	6.15	BSC	.242	BSC

TO-268 Outline


SYM	INCHES		MILLIMETERS	
	MIN	MAX	MIN	MAX
A	.193	.201	4.90	5.10
A1	.106	.114	2.70	2.90
A2	.001	.010	0.02	0.25
b	.045	.057	1.15	1.45
b2	.075	.083	1.90	2.10
C	.016	.026	0.40	0.65
C2	.057	.063	1.45	1.60
D	.543	.551	13.80	14.00
D1	.488	.500	12.40	12.70
E	.624	.632	15.85	16.05
E1	.524	.535	13.30	13.60
e	.215	BSC	5.45	BSC
H	.736	.752	18.70	19.10
L	.094	.106	2.40	2.70
L1	.047	.055	1.20	1.40
L2	.039	.045	1.00	1.15
L3	.010	BSC	0.25	BSC
L4	.150	.161	3.80	4.10

IXYS reserves the right to change limits, test conditions, and dimensions.

IXYS MOSFETs and IGBTs are covered by one or more of the following U.S. patents:

4,835,592	4,881,106	5,017,508	5,049,961	5,187,117	5,486,715	6,306,728B1
4,850,072	4,931,844	5,034,796	5,063,307	5,237,481	5,381,025	

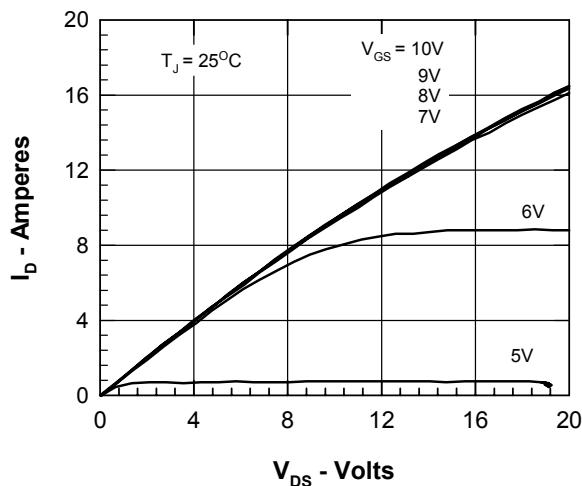


Figure 1. Output Characteristics at 25°C

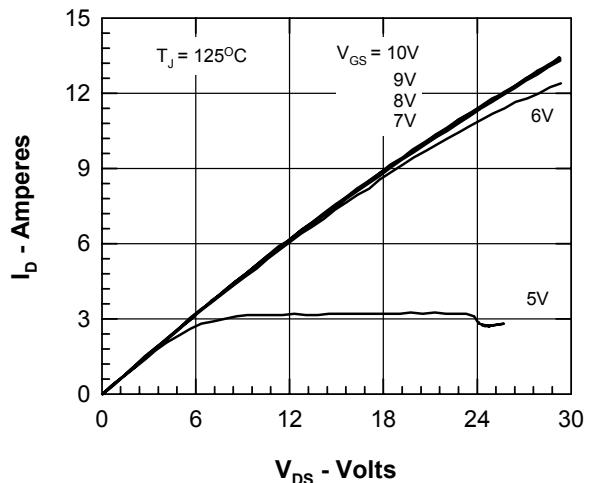


Figure 2. Output Characteristics at 125°C

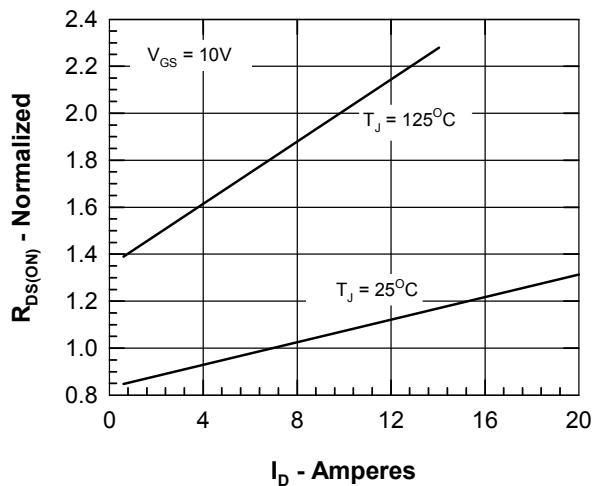


Figure 3. $R_{DS(on)}$ normalized to value at $I_D = 12A$

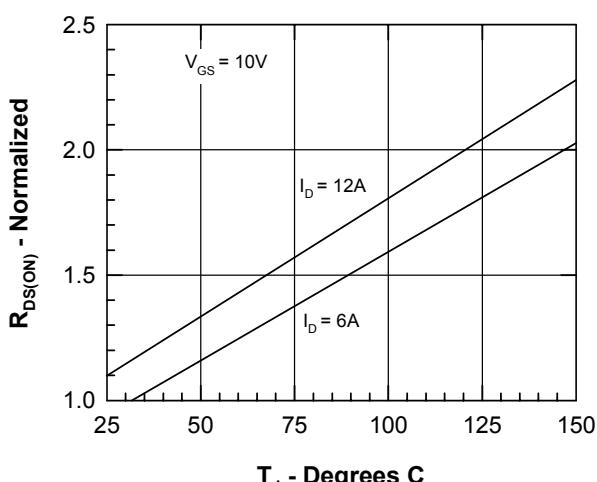


Figure 4. $R_{DS(on)}$ normalized to value at $I_D = 12A$

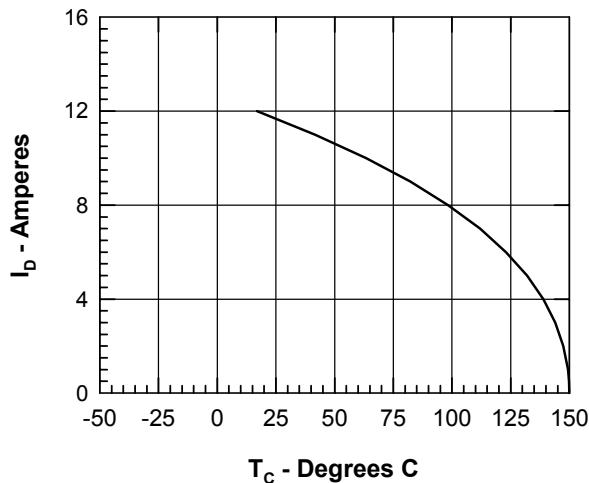


Figure 5. Drain Current vs. Case Temperature

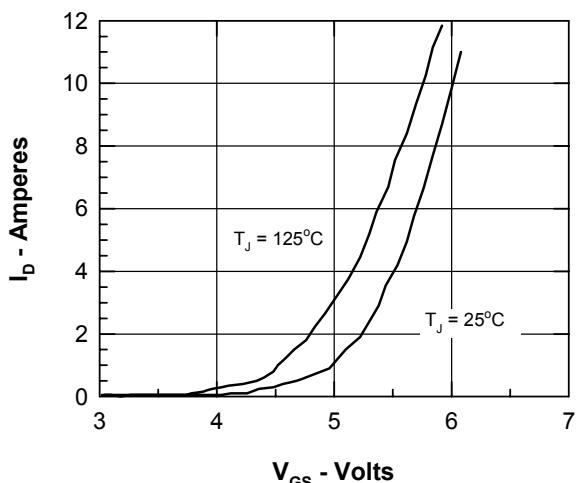


Figure 6. Admittance Curves

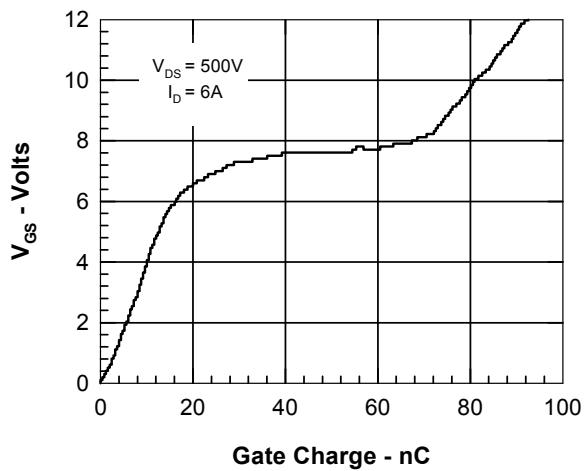


Figure 7. Gate Charge

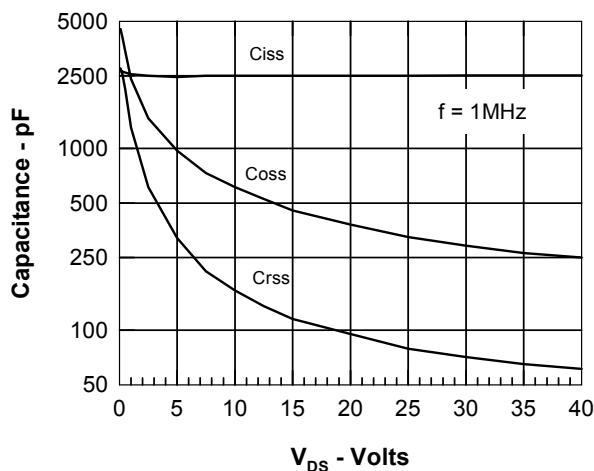


Figure 8. Capacitance Curves

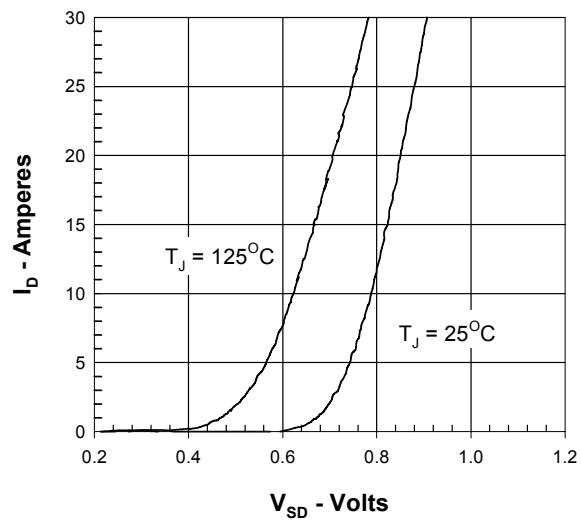


Figure 9. Source Current vs. Source to Drain Voltage

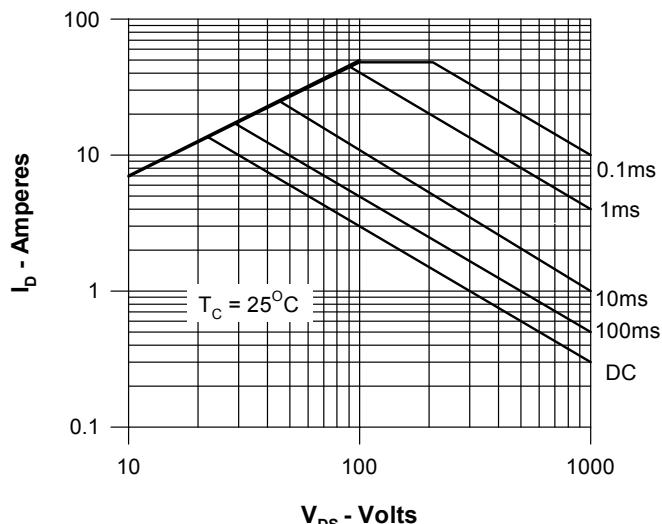


Figure 10. Forward Bias Safe Operating Area

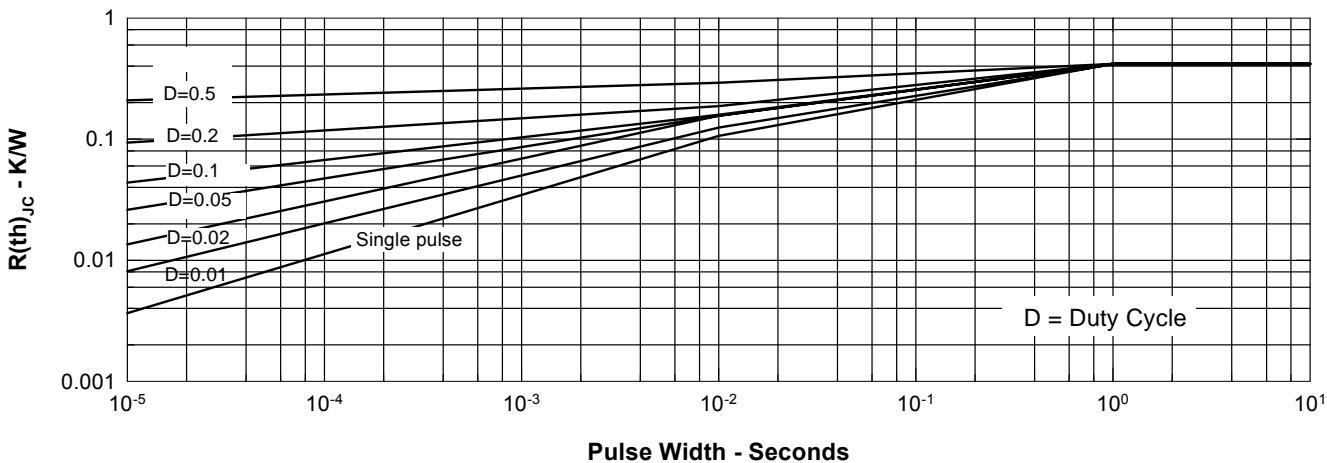


Figure 11. Transient Thermal Resistance

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4,850,072	4,931,844	5,034,796	5,063,307	5,237,481	5,381,025	



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